



# Understanding EUV Resist Performance Using Scanning Probe Microscopy

Paul Ashby

Staff Scientist

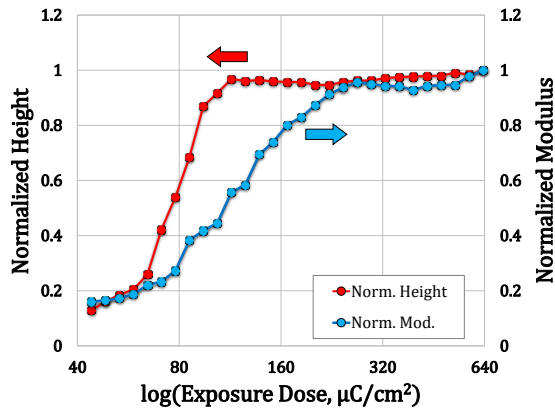
Imaging and Manipulation Facility

Molecular Foundry

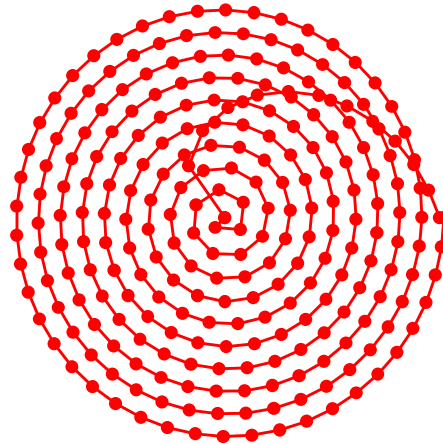


# Outline

## EUV resist design and characterization



## High speed Spiral Scan AFM

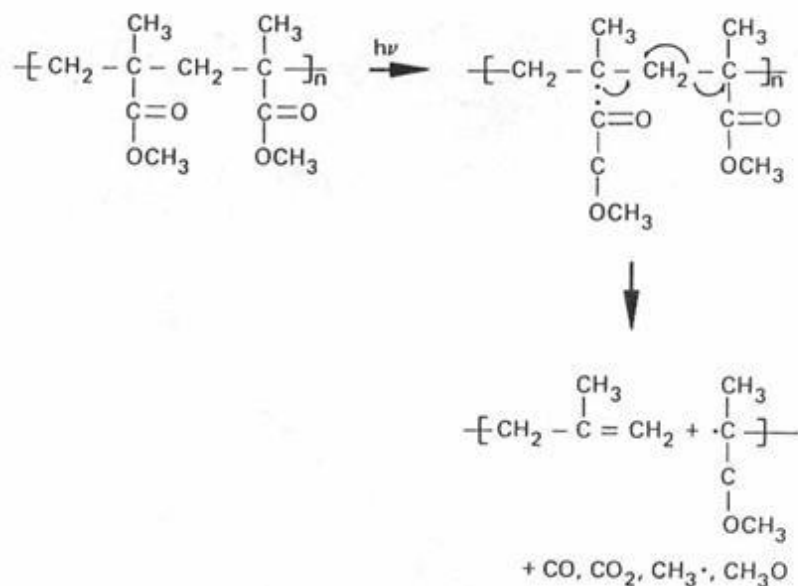


## Encased Cantilevers for In-situ AFM

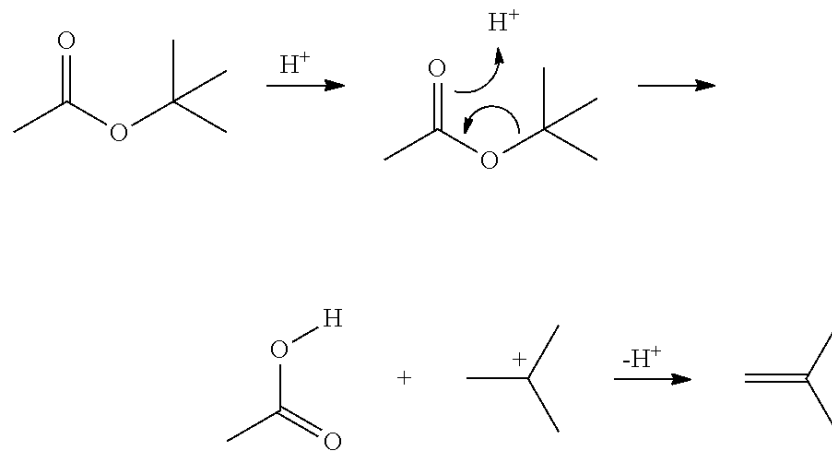


# Chemical Contrast Mechanisms

## Entropic

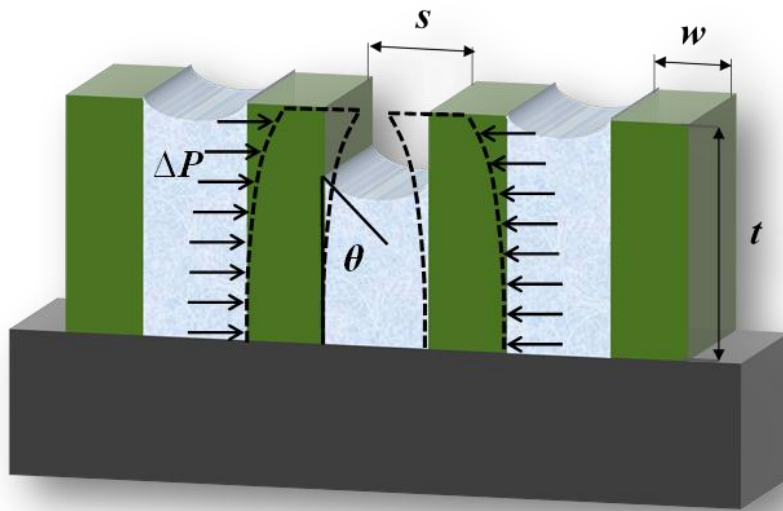


## Enthalpic



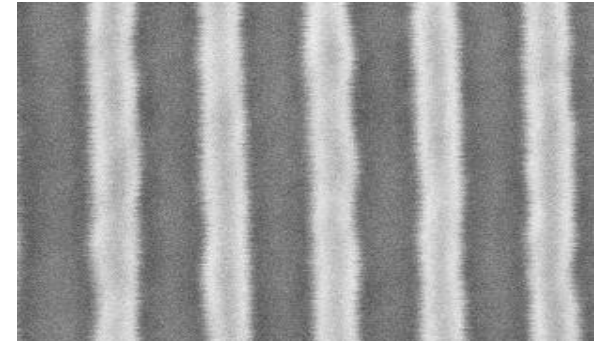
# Factors limiting resist performance

- Pattern Collapse
- Swelling
- Poor Line Edge Roughness

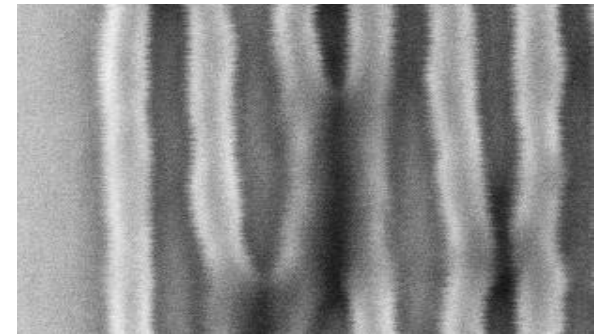


Capillary Induced  
Pattern Collapse

60 pitch



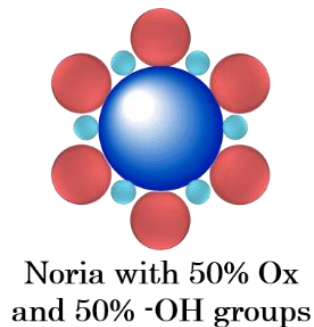
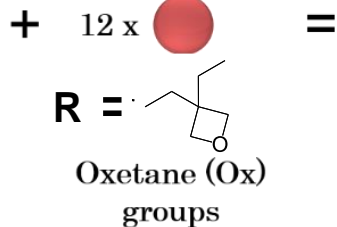
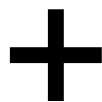
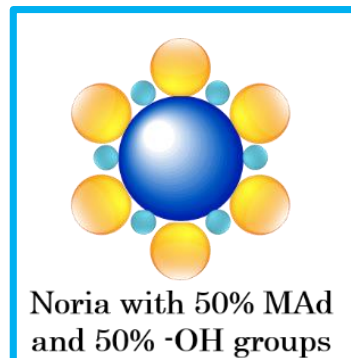
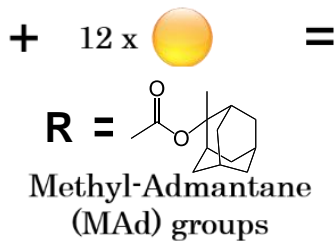
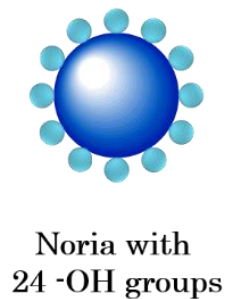
48 pitch



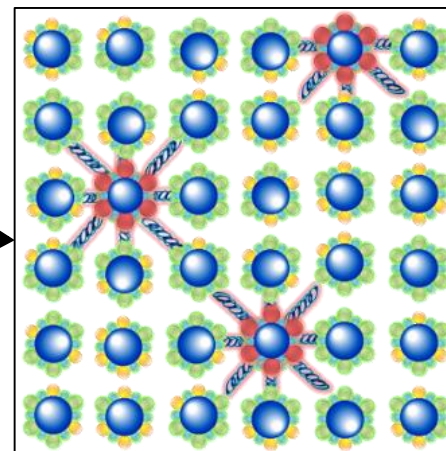
$$\frac{E}{g} \leq \frac{8}{w_s} A_l^3 (3A_s \cos q + \sin q)$$



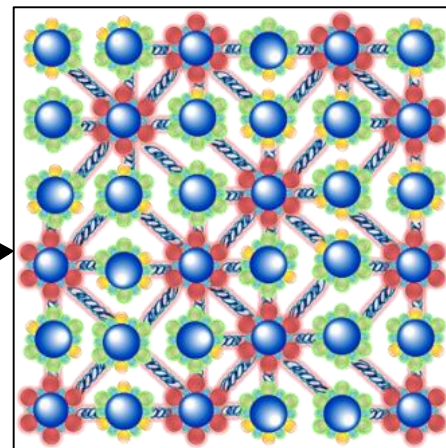
# Combining cross-linking and chemical amplification



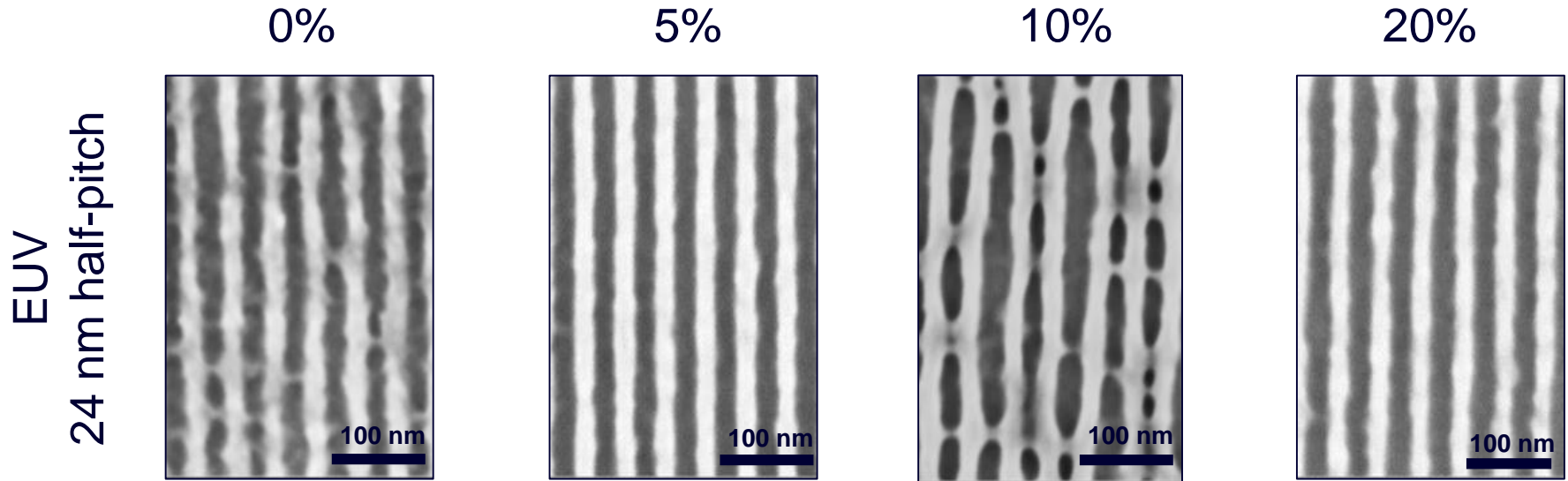
Low Noria-Ox



High Noria-Ox



# Cross-linking resist performance

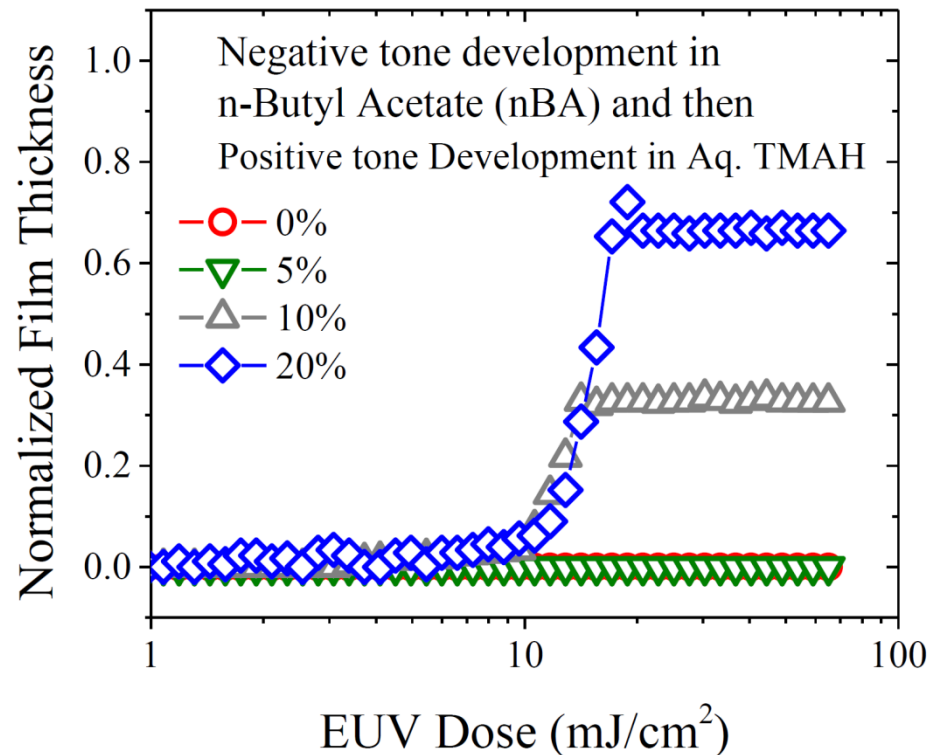


5% oxetane cross-linkers in the resist solution patterns to higher resolution with lower line edge roughness.

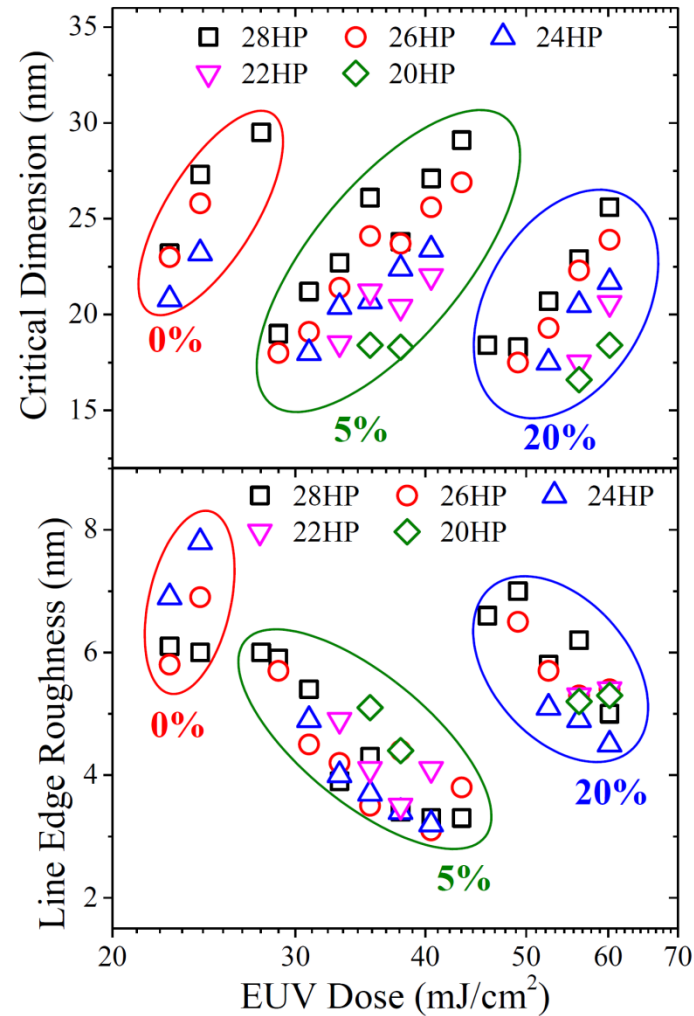
Negative tone development using n-butyl acetate.

# Best performer not highly cross-linked

## Double development



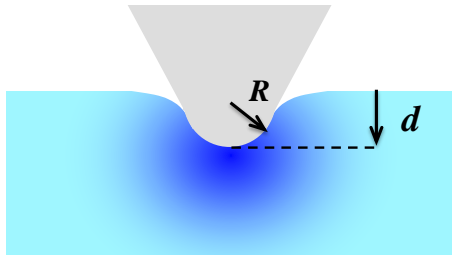
# Improved process window



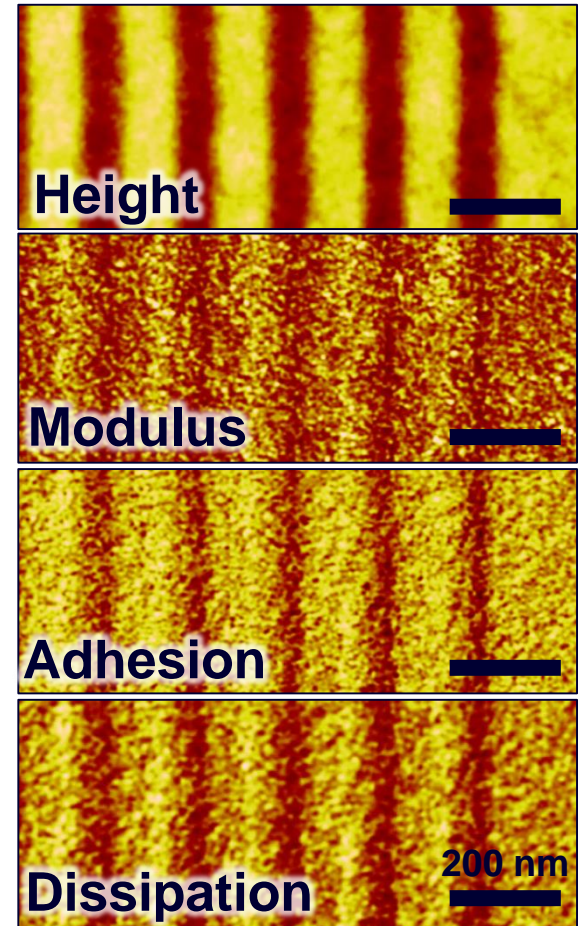
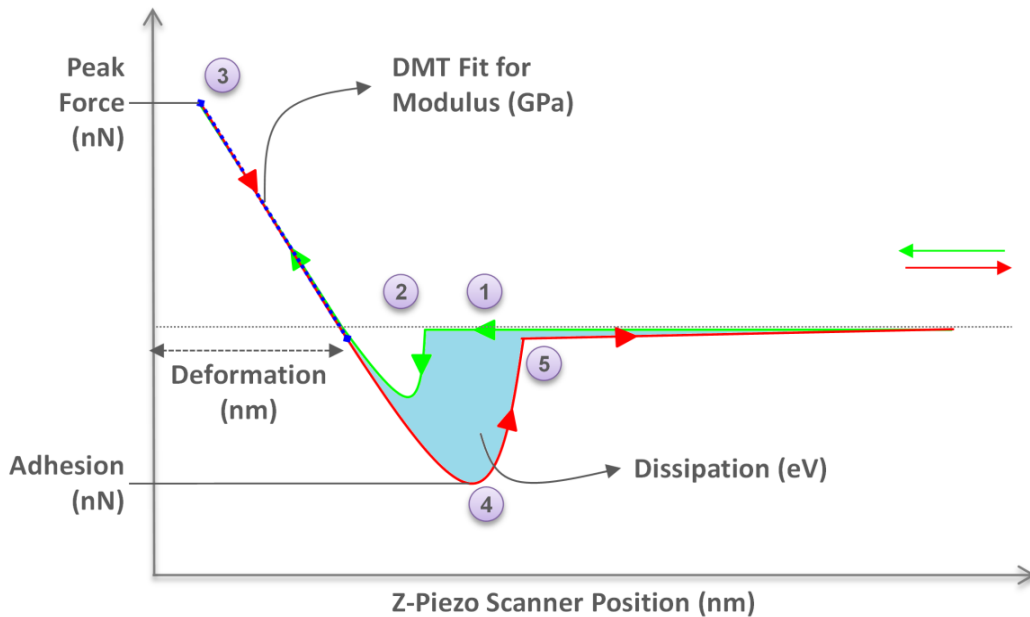


# Nanomechanical mapping

$$F_{tip} = \frac{4}{3} E_r \sqrt{Rd^3} + F_{adh} = kx$$

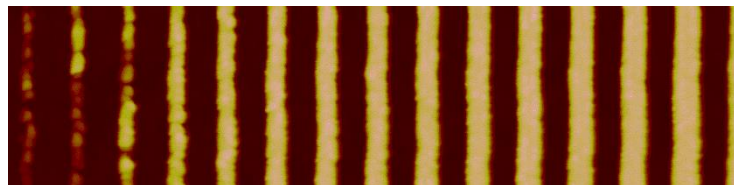


PeakForce™ AFM

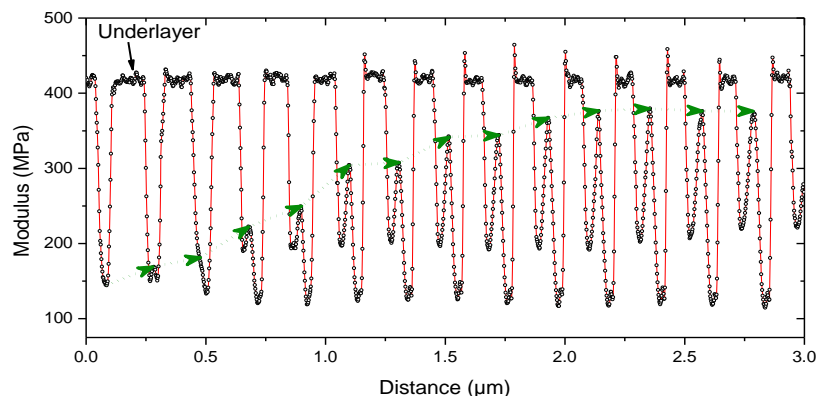
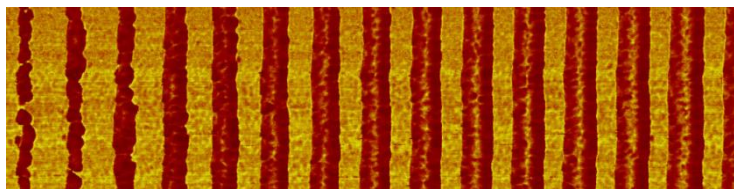


# Modulus measures chemical change

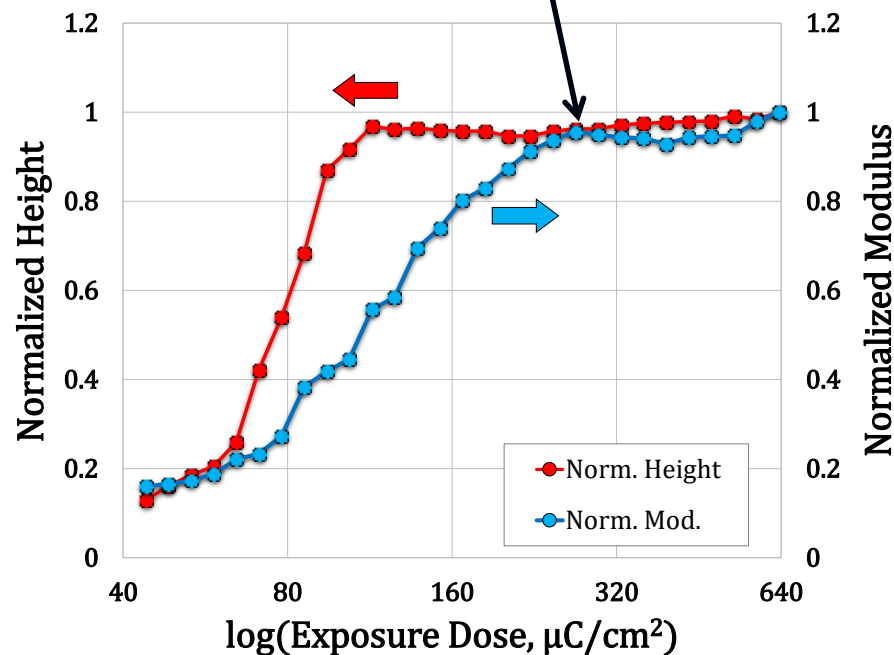
Height



Modulus



Optimum pattern

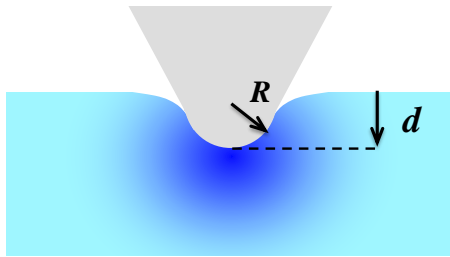


Modulus shows chemistry through dose past full thickness and is a good nanoscale measure of chemical change.

# Acknowledgements

## Novel EUV Resist Material and Mechanical Characterization

$$F_{tip} = \frac{4}{3} E_r \sqrt{Rd^3} + F_{adh} = kx$$



Prashant Kulshreshtha (Molecular Foundry)  
Deirdre Olynick (Molecular Foundry)  
James Blackwell (Intel)  
Ken Maruyama (JSR Micro)  
Sara Kiani (Molecular Foundry)  
Scott Dhuey (Molecular Foundry)  
Weilun Chao (CXRO)  
Patrick Naulleau (CXRO)

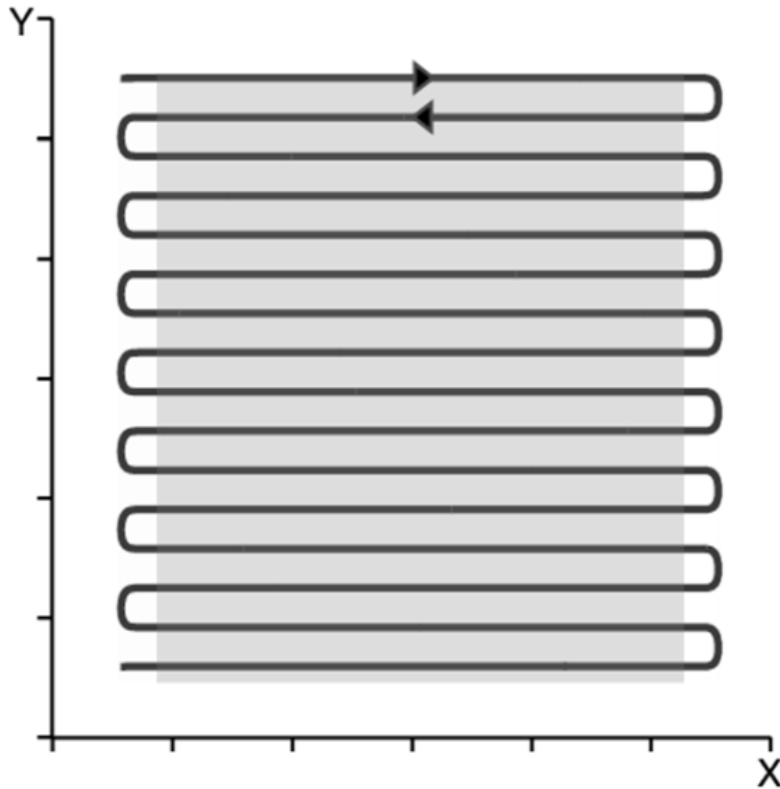


Kulshreshtha et. al., Nanotechnology 25 315301 (2014)  
doi:10.1088/0957-4484/25/31/315301

Kulshreshtha et. al., SPIE Advances in Patterning Materials and Processes XXXII, (2015), doi:10.1117/12.2086045.



# Rasterkraftmikroskopie



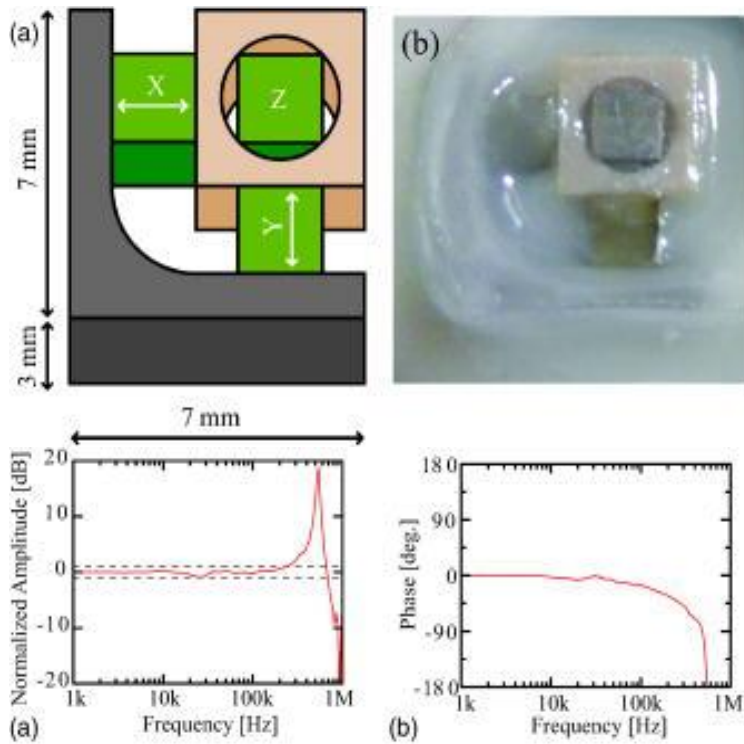
Raster scanning saved bandwidth.

Requires constant velocity and high acceleration at the turnarounds.

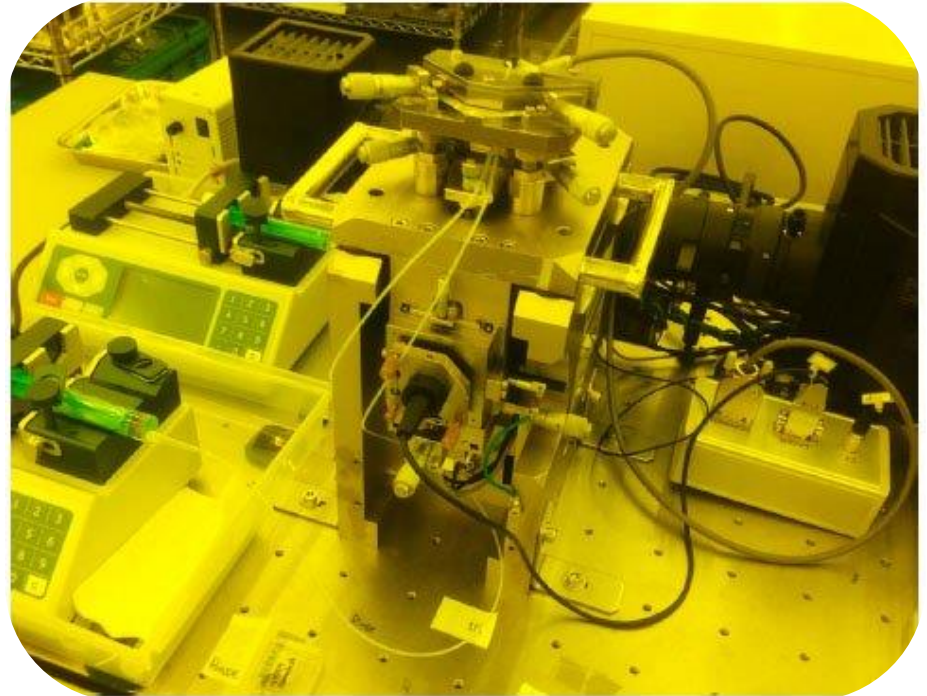
Throw away half the data per image.



# High Speed AFM

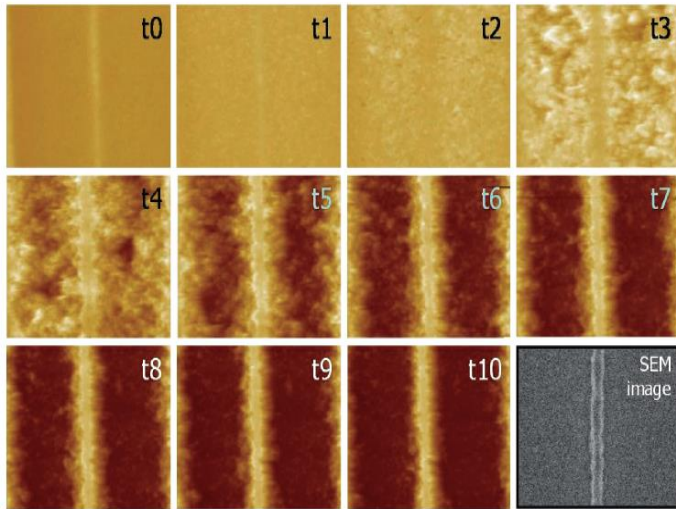


Ando et. al., APL, 92, 243119 (2008)

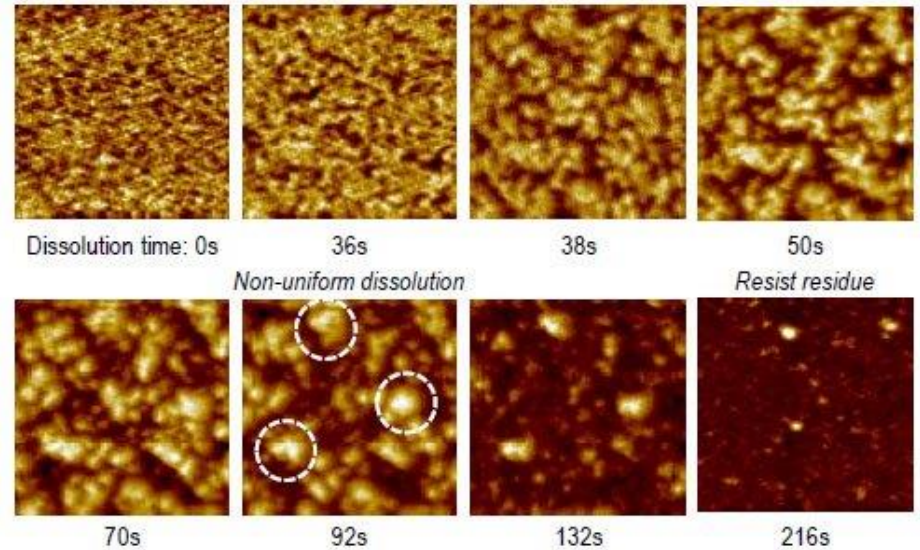


EUVL Infrastructure Development Ctr., Inc.

# Resist Development by HSAFM



Toshiro Itani and Julius Joseph Santillan,  
Applied Physics Express, 3, 061601 (2010)

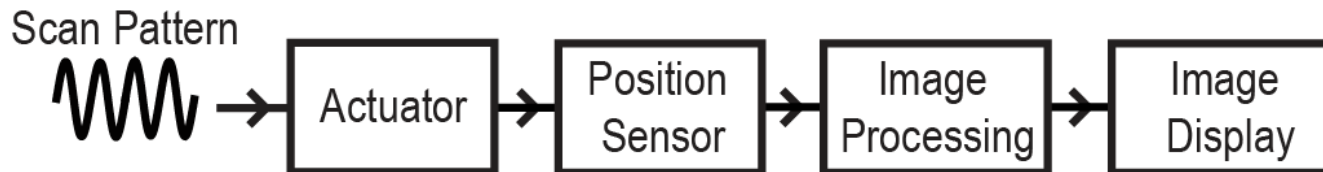


Toshiro Itani and Julius Joseph Santillan,  
Advanced Lithography 2018 DOI:10.1117/12.2294585

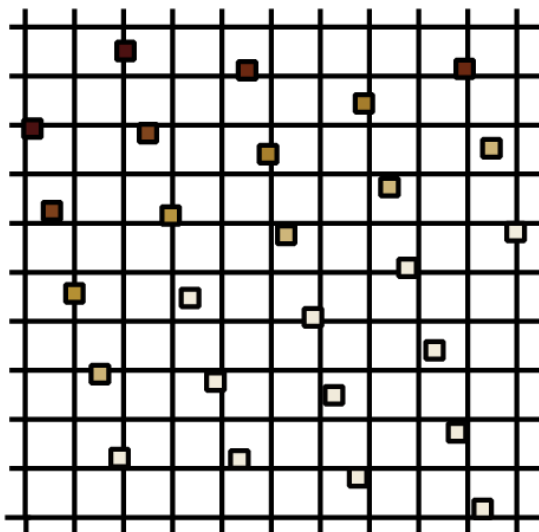


# Breaking the paradigm

## Sensor Inpainting

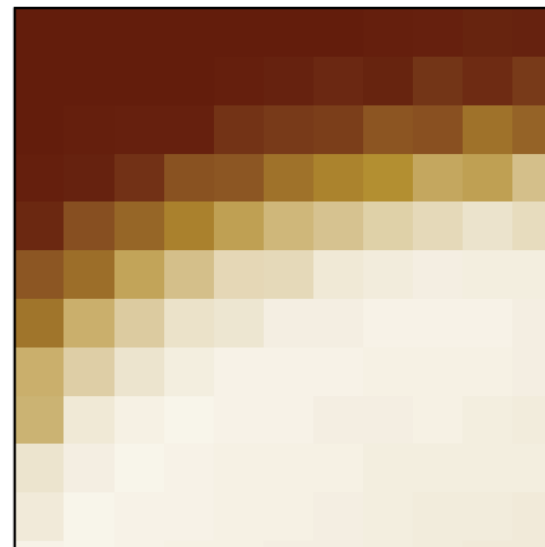


Non-Gridded Sensor Data

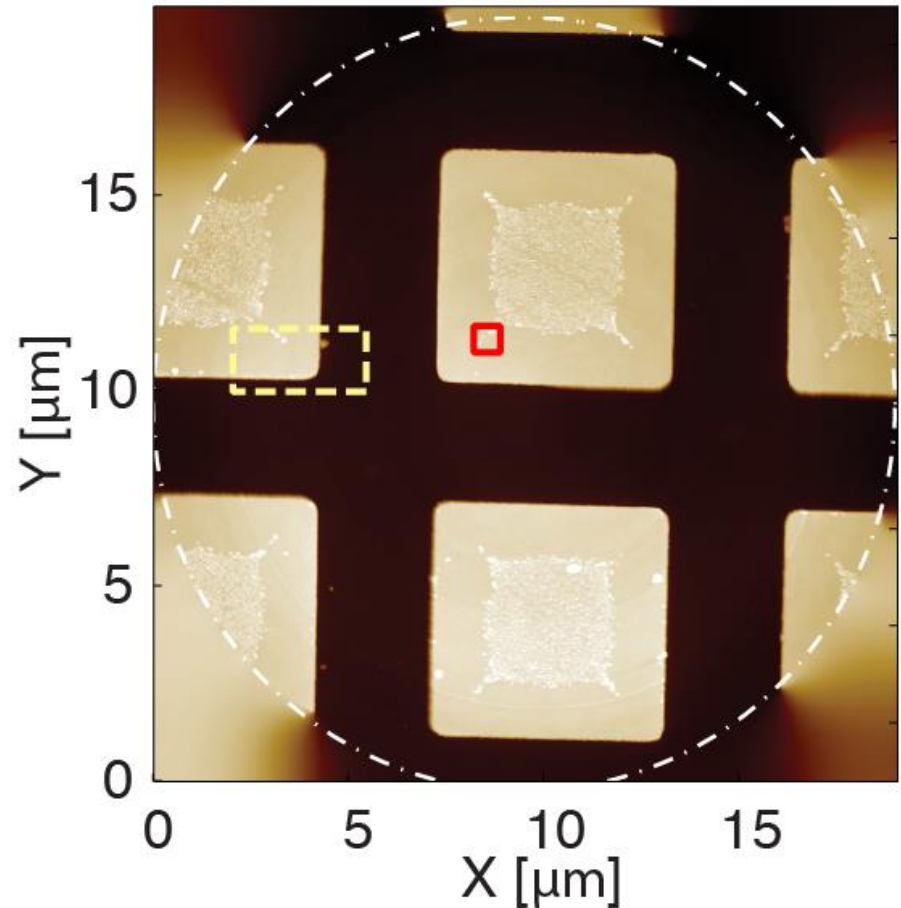
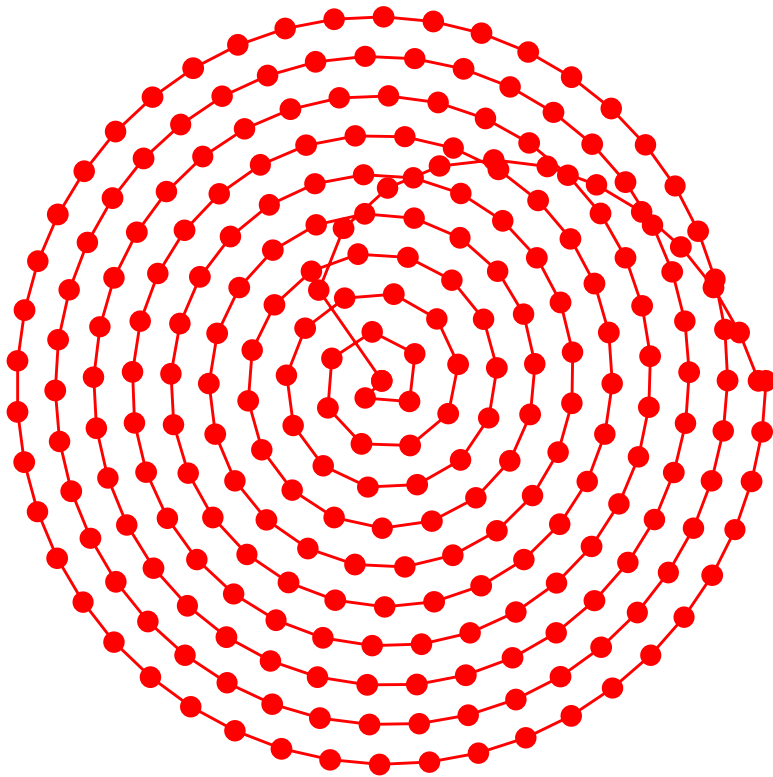


$$E(u) = \int_{\Omega} |\nabla u|^2 + \int_D (u - f)^2$$

Final Rendered Image



# Spiral scanning

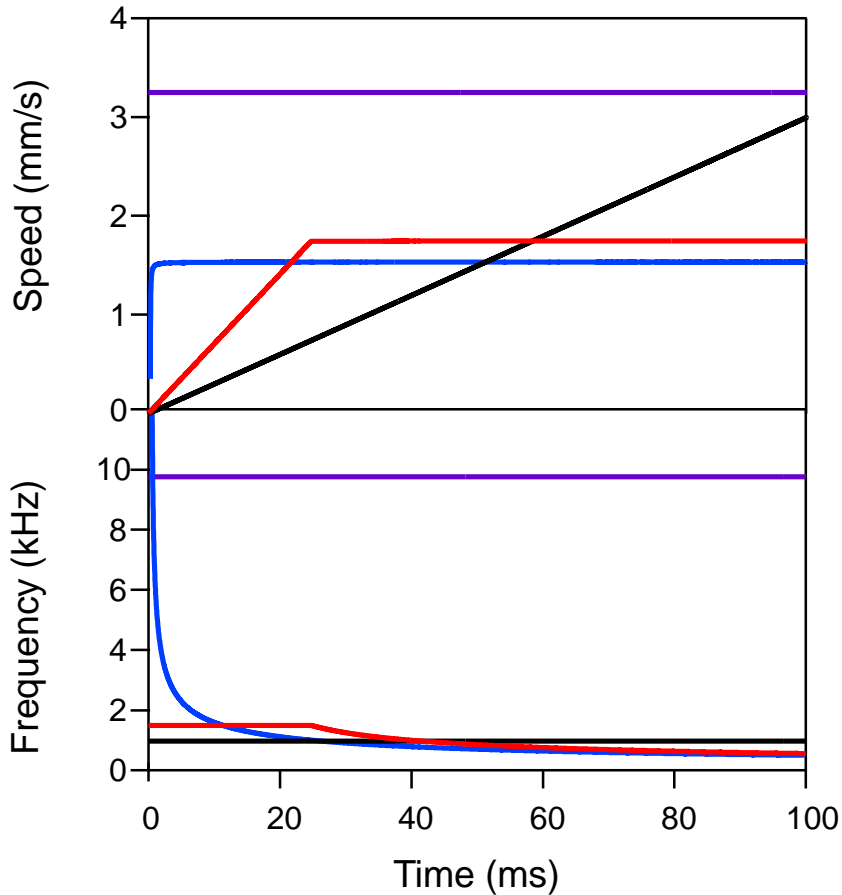


Utilizes almost 100% of the scan time.

All scan lines are in same direction.

# The Optimal Spiral

## Spiral Scans vs Raster scan



Archimedean  
Spiral  
(even spacing)

$$r \propto \theta$$

Constant  
Linear  
Velocity

$$\theta \propto \sqrt{t}$$



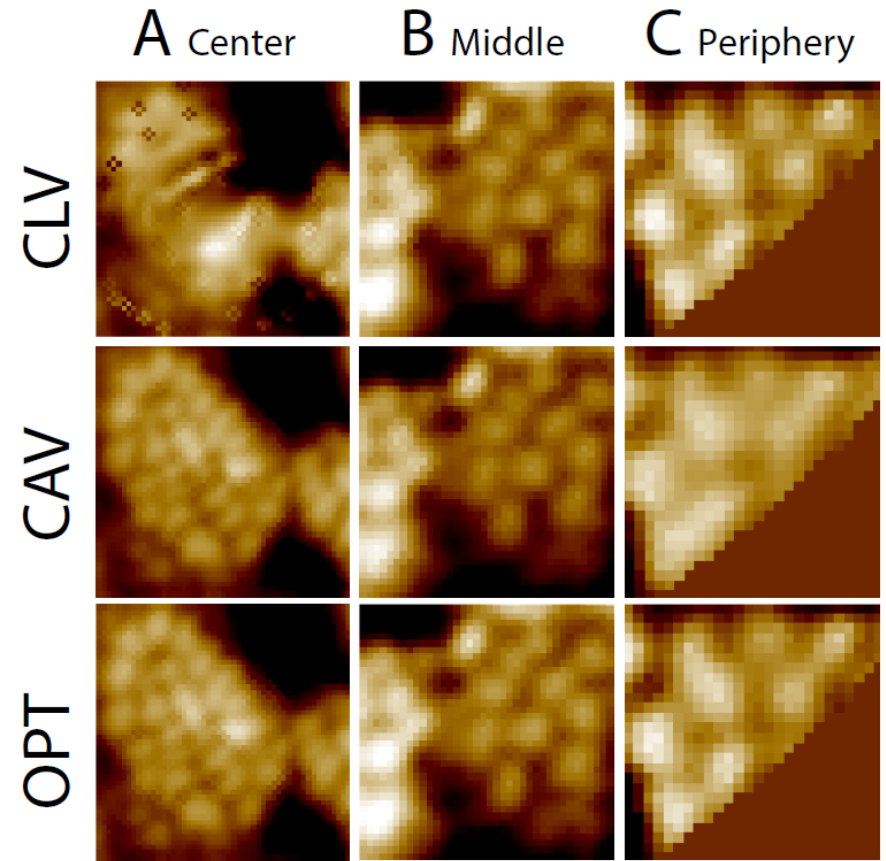
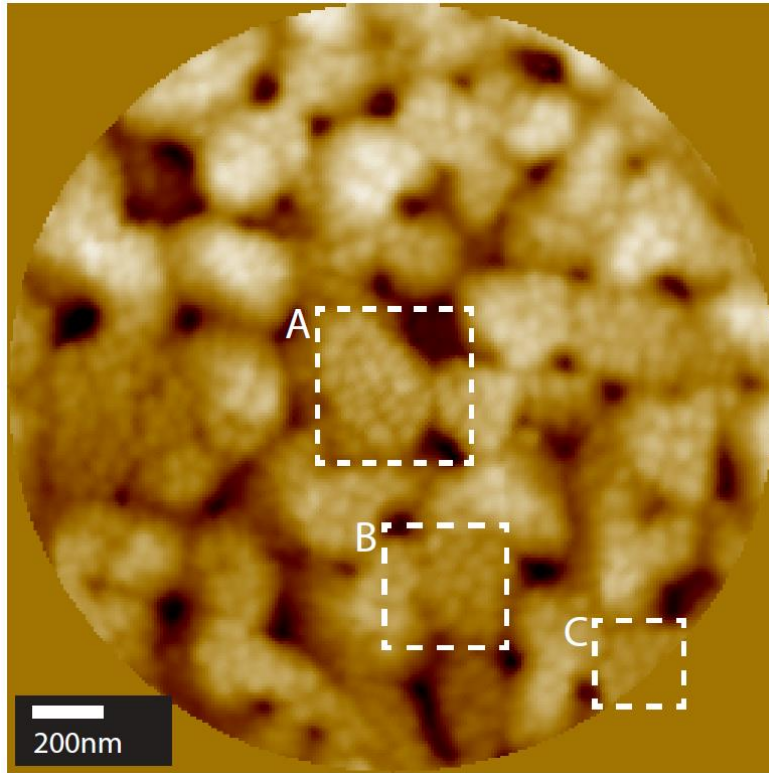
Constant  
Angular  
Velocity

$$\theta \propto t$$

**Optimal Spiral**

Optimal Spiral is safest and fastest!

# Spiral Comparison



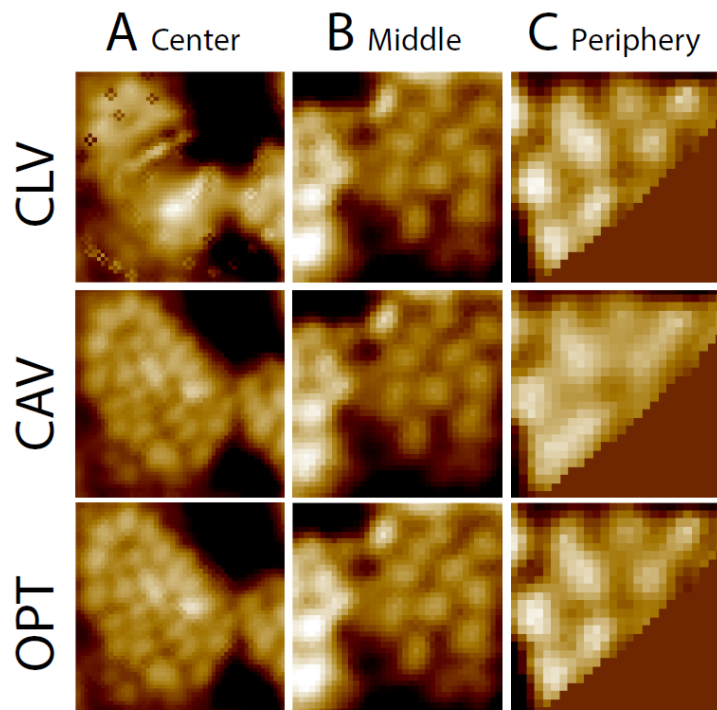
Optimal spiral has highest fidelity over the whole image.

# Alternate Waveform Comparison

	Raster	Spirograph	Lissajous	CLV	CAV	OPT
Maximum Angular Frequency	> 9.0	3.1	2.0	>50	1.0	2.1
Angular frequency Variation	>1.5	0	0	1.2	0	0.5
Speed	2.3	3.1	4.9	1.0	2.0	~1.1
Average Sample Density	0.4	1.0	1.0	0.95	0.95	0.95
Maximum Sample Density	1	22	49	1	39	19
Sample Density Variation	0	0.3	0.5	0	0.39	0.04
Data Prioritizes Center	---	---	x	---	✓	✓
Adjacent Scan Lines are similar	✓	x	x	✓	✓	✓

# Acknowledgements

High speed Spiral Scan AFM



Dominik Ziegler (Molecular Foundry)  
Andrea Bertozzi (UC Los Angeles)  
Travis Meyer (UC Los Angeles)  
Adrian Nievergelt (Molecular Foundry)  
Andreas Amrein (ETH Zurich)

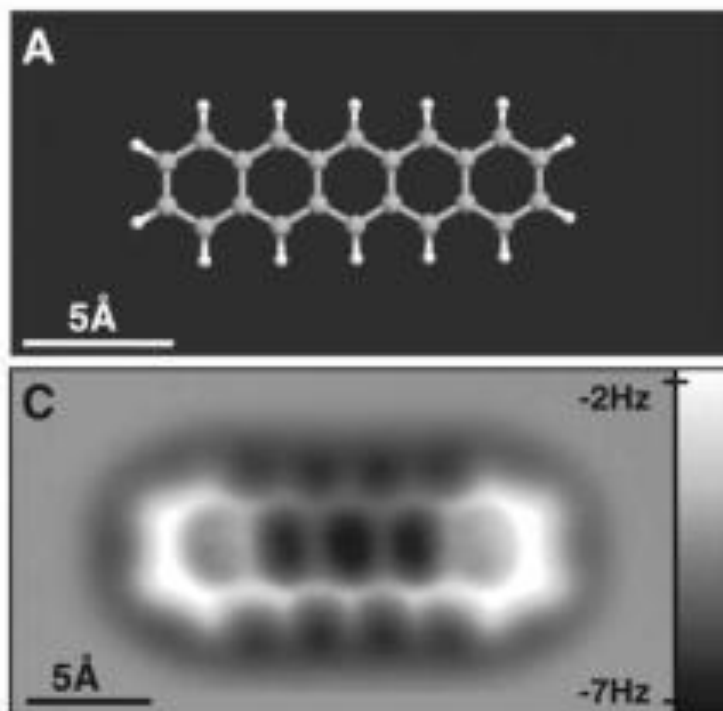


Ziegler, et. al., Nanotechnology, v24, 335703, 2013

Ziegler, et. al., IEEE Mechatronics, v22, p381-391, 2016.

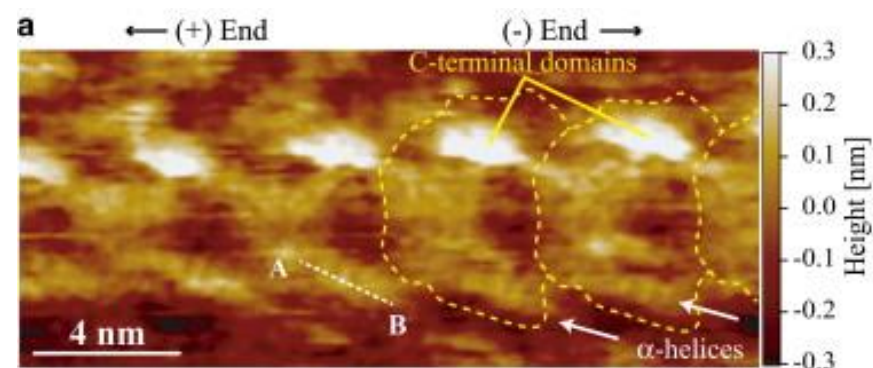


# Liquid Compromises Resolution



Pentacene

Gross, et. al. *Science* v325 p1110 (2009)



Tubulin filament

Fukuma, et. al., *Biophysical Journal* v101 p1270 (2011)

# Low Force Noise Cantilevers

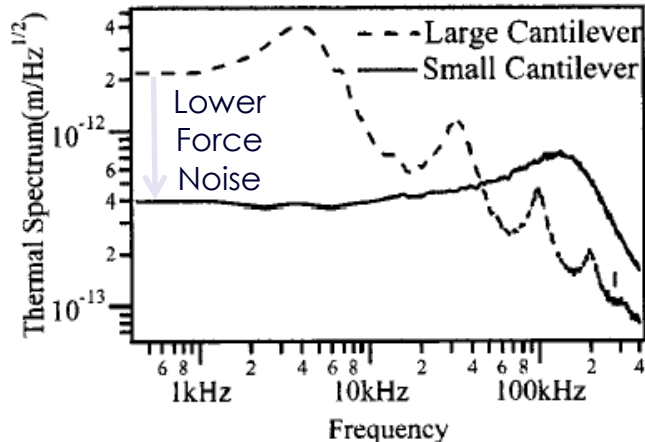
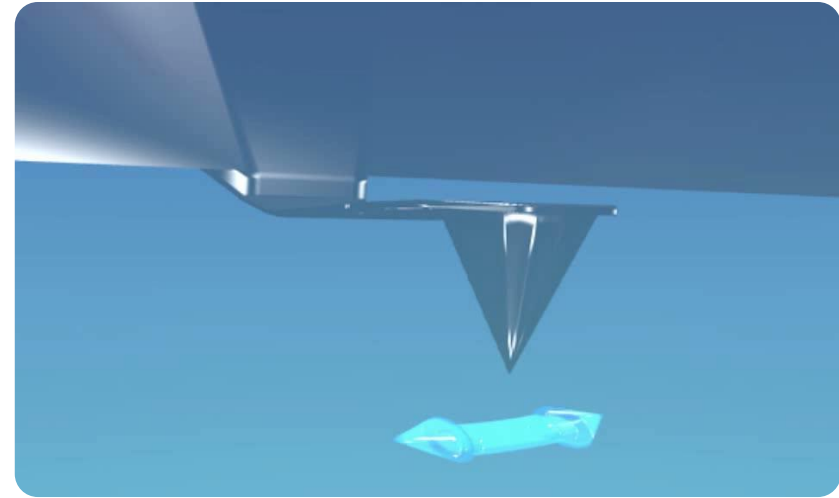
$$F_n = \sqrt{4k_B T b}$$

$$b = 6\pi R \eta$$

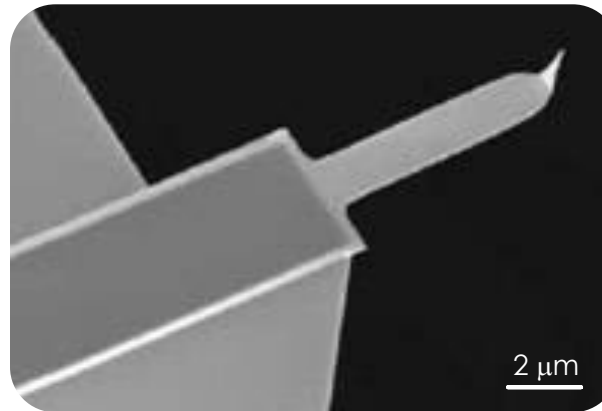
Size of object      Viscosity

$$F_n = 7 \text{ fN}/\sqrt{\text{Hz}}$$

Laser Tweezers



Viani et. al. JAP v86 p2258 (1999)



Olympus BioleverFAST

Force Noise  
 $F_n = 23 \text{ fN}/\sqrt{\text{Hz}}$

Requires high NA instrument

# Encased Cantilevers

Changing  $\eta$



# Encased Cantilever Fabrication

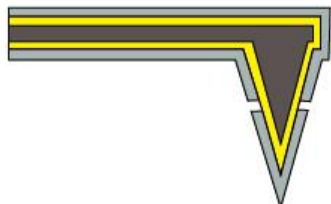
Regular Si Cantilever



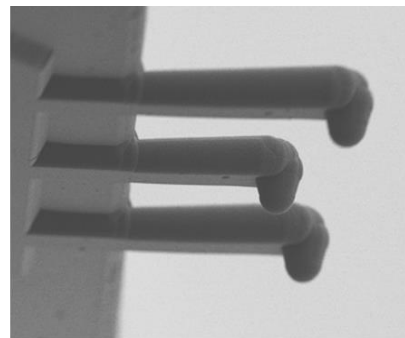
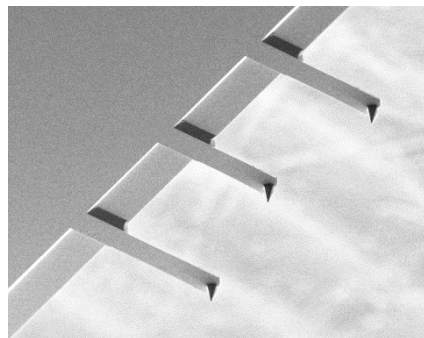
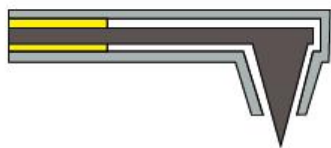
PECVD



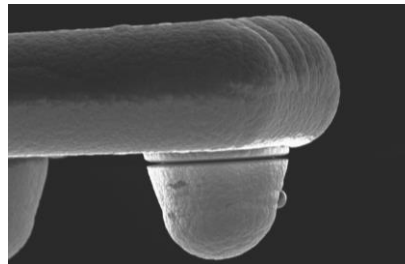
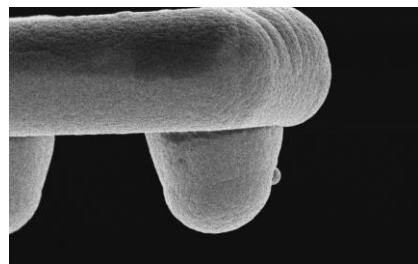
FIB Opening



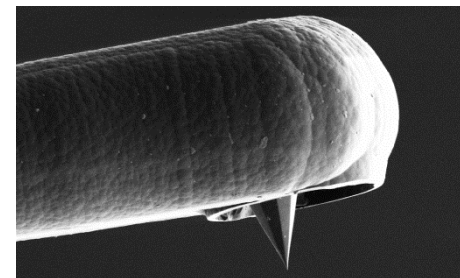
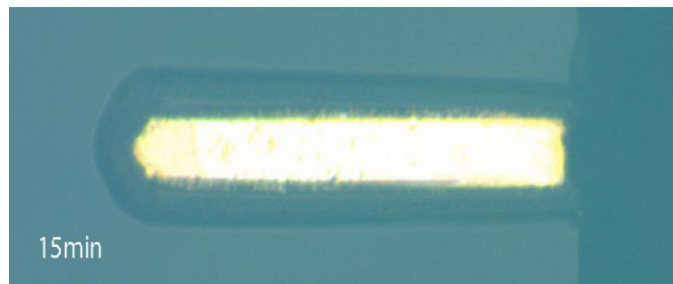
Sacrificial Layer Etching



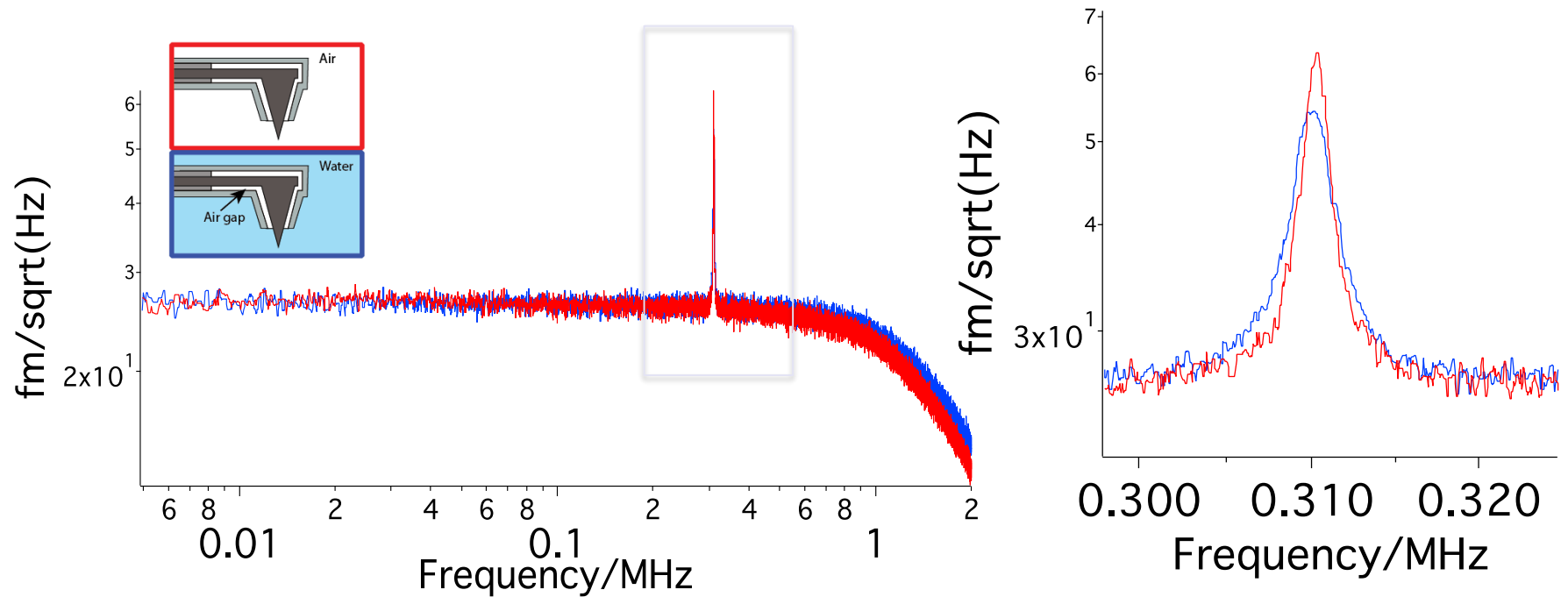
125  $\mu\text{m}$  long  
30  $\mu\text{m}$  wide  
40 N/m, 300 kHz,  
Q~500  
25 fN/ $\sqrt{\text{Hz}}$



20  $\mu\text{m}$  long  
10  $\mu\text{m}$  wide  
1 N/m, 1 MHz,  
Q~200  
3.5 fN/ $\sqrt{\text{Hz}}$



# Encased Cantilever Performance



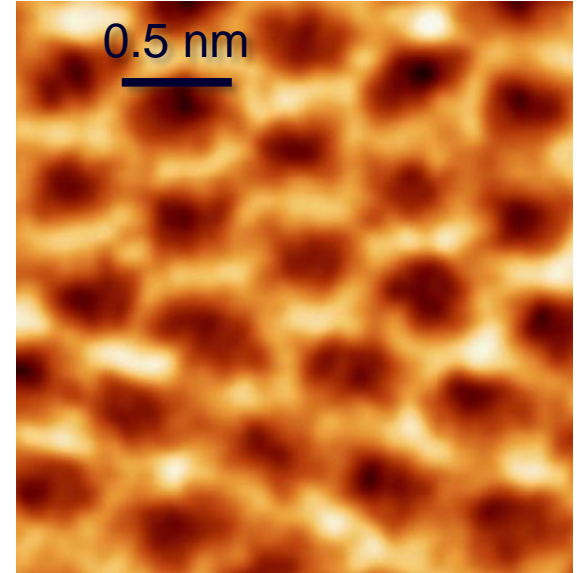
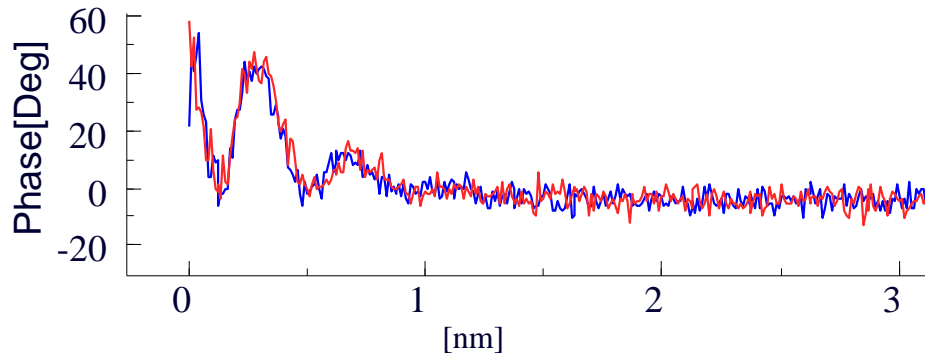
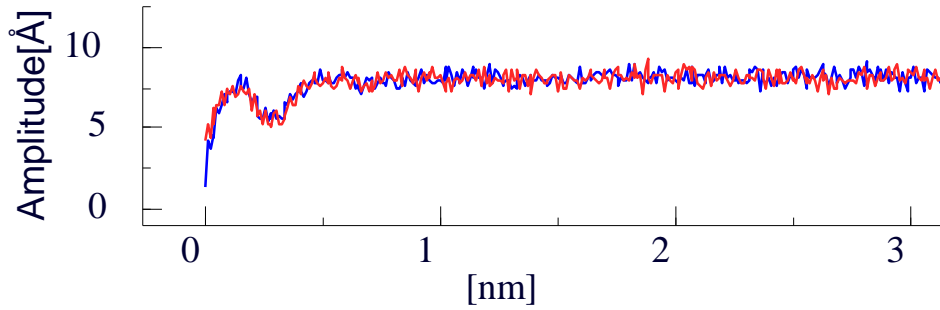
Single clean resonance peak.

High Q and high frequency, performance as in air ( $F_n = 12 \text{ fN}/\sqrt{\text{Hz}}$ )

-Only small frequency shift (1%)  $\rightarrow$  No Added Mass

-Viscous damping of tip (few  $\mu\text{m}$ ) and double sided squeeze film damping

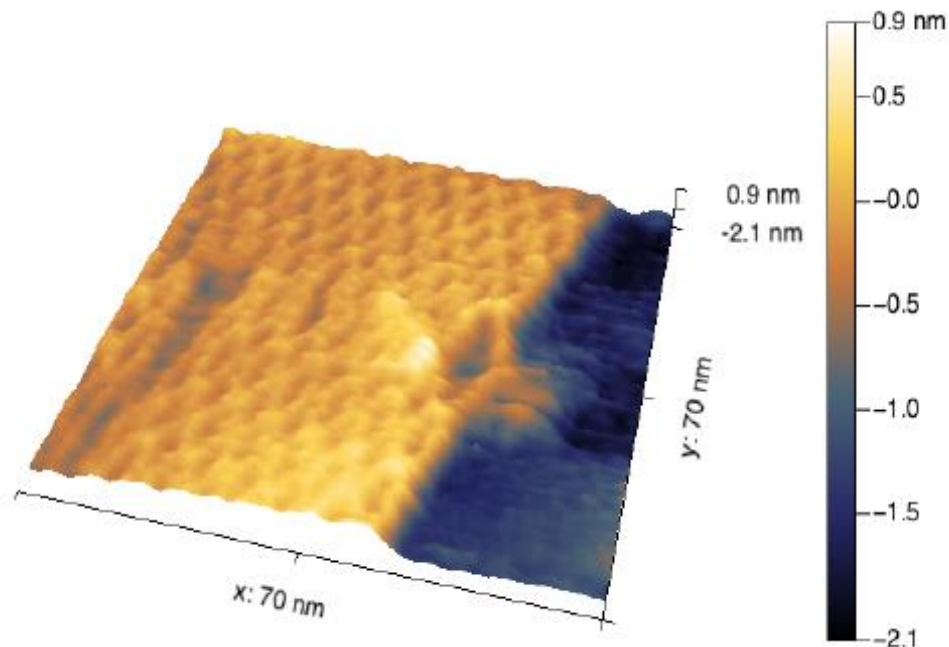
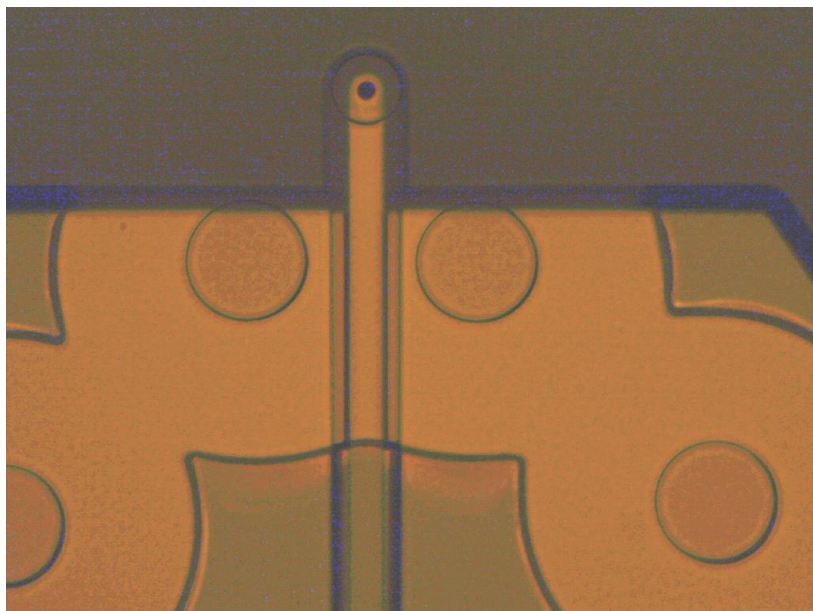
# Water at Mica



Ultra-small amplitude  
displacement of the last few water layers  
single curve no averaging



# Present Day Encased Cantilevers



SCUBA PROBE  
TECHNOLOGIES



# Acknowledgements

Encased Cantilevers  
for In-situ AFM



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John Sader (University of Melbourne)

Sina Sidighi (SPT)

Christina Newcomb (SPT)

Hilary Brunner (SPT)

Remo Blum (SPT)



SCUBA PROBE  
TECHNOLOGIES

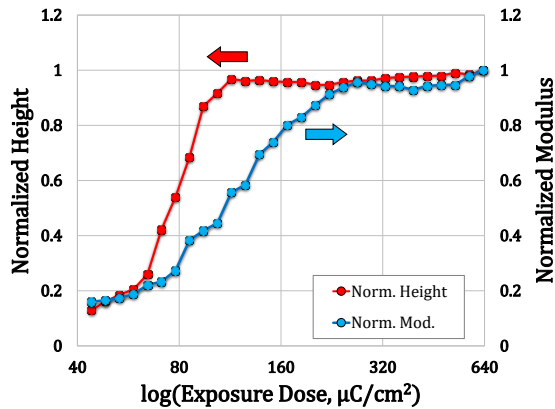
Ziegler, Ashby, et. al., IEEE MEMS, p128, 2014 DOI:10.1109/MEMSYS.2014.6765590.

Desbiolles et. al., Beilstein J. Nanotechnol., 9, 1381-1389, (2018)  
doi:10.3762/bjnano.9.130.

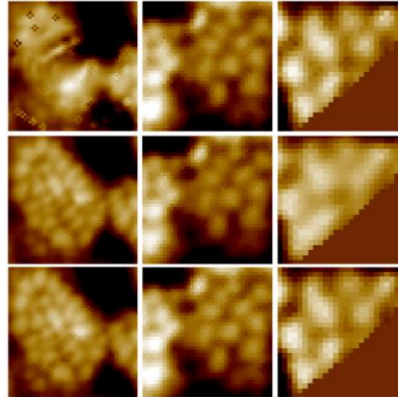
**MOLECULAR  
FOUNDRY** 

# Conclusion

## EUV resist design and characterization



## High speed Spiral Scan AFM

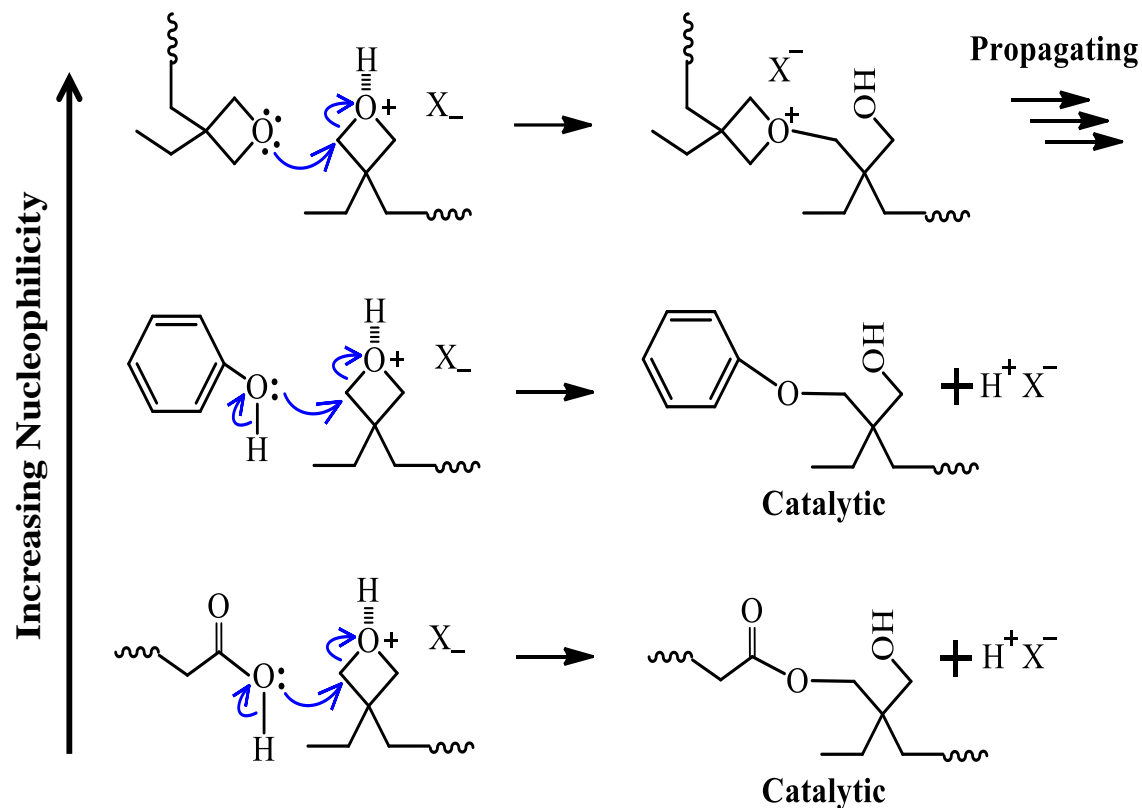
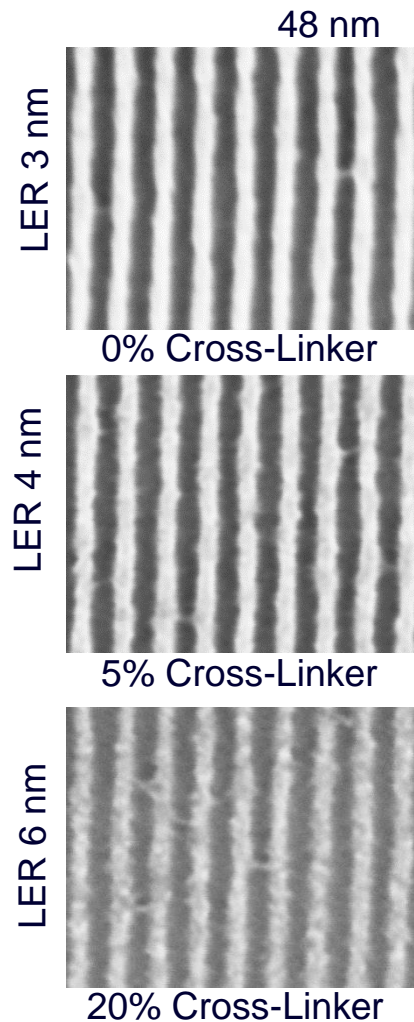


## Encased Cantilevers for In-situ AFM

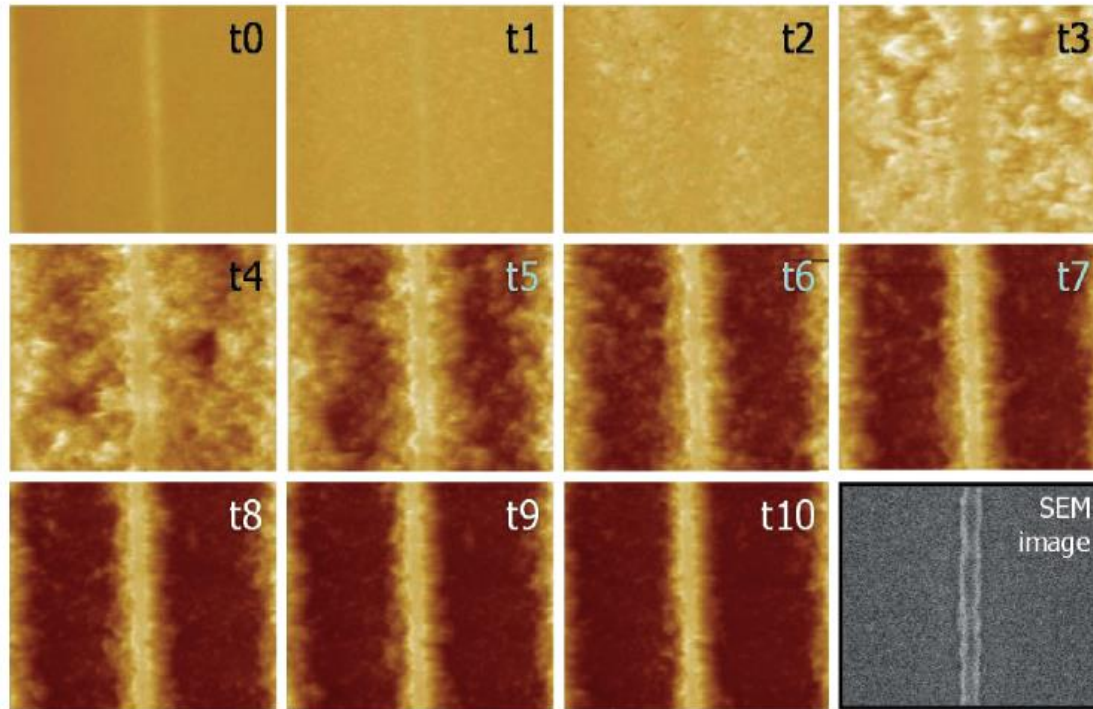




# High-Amounts of Cross-linker Due to Chain Propagating Reaction



# Resist dissolution



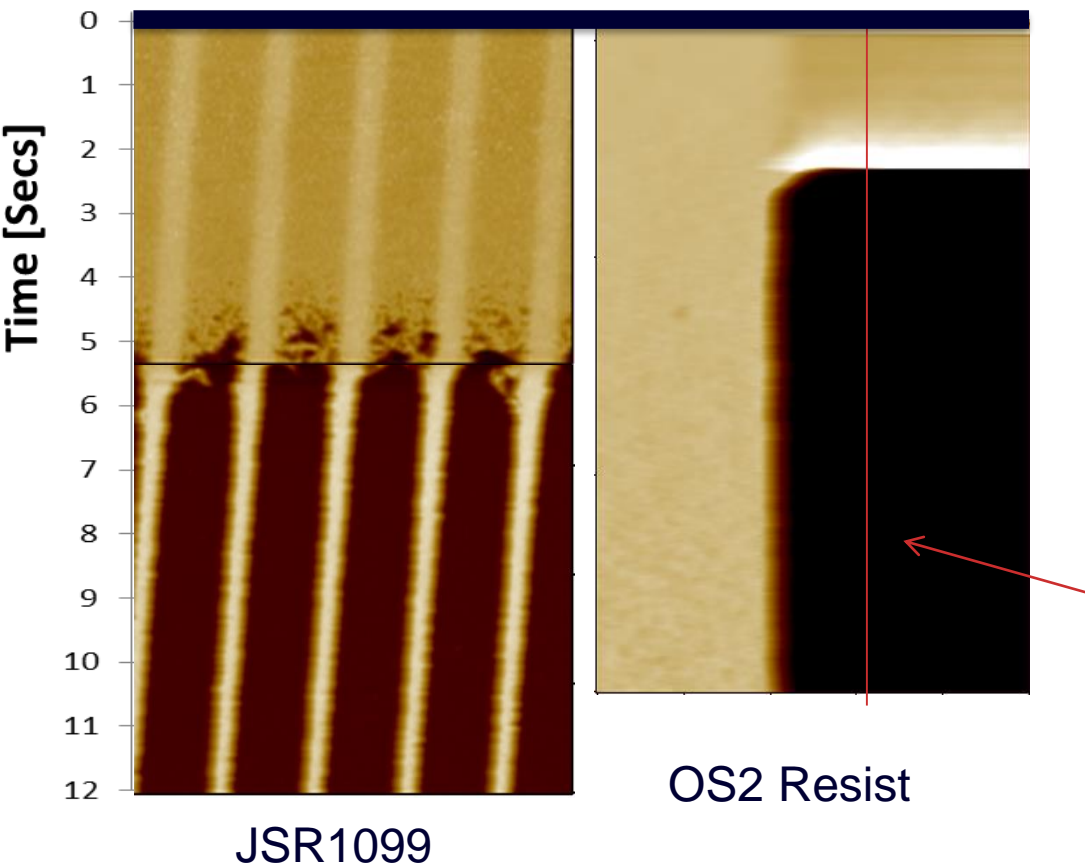
Toshiro Itani and Julius Joseph Santillan,  
Applied Physics Express, 3, 061601 (2010)



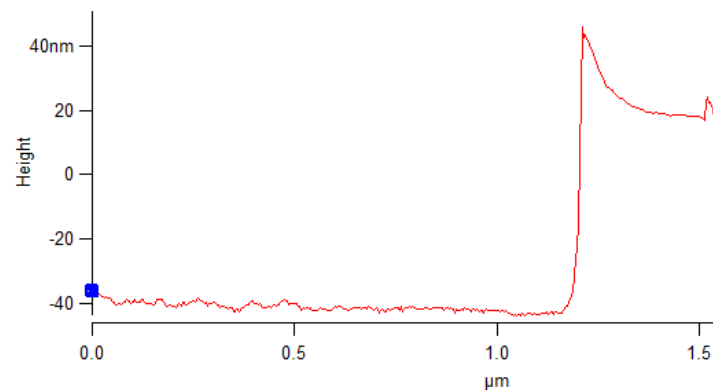


# Sematech efforts at the Foundry

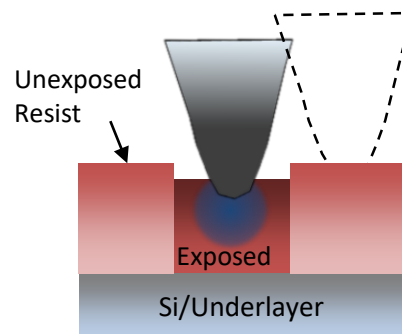
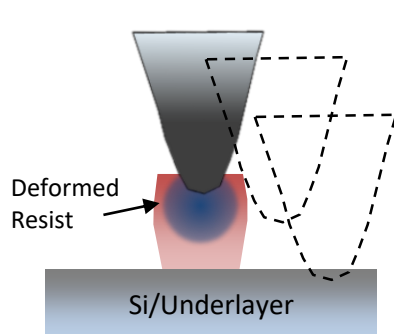
Start of developer injection



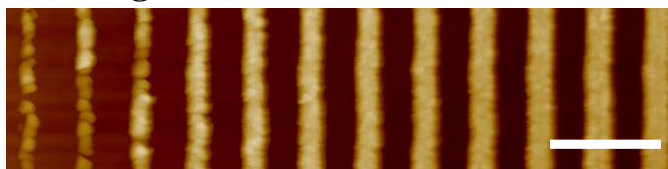
Asylum Research Cypher  
(40 lines/s)



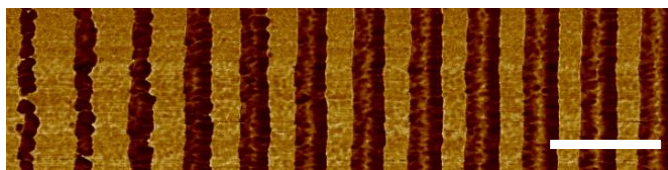
# Latent image gives higher resolution



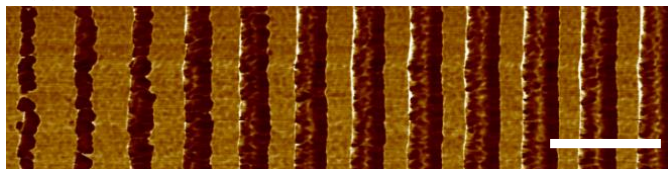
**(a) Height**



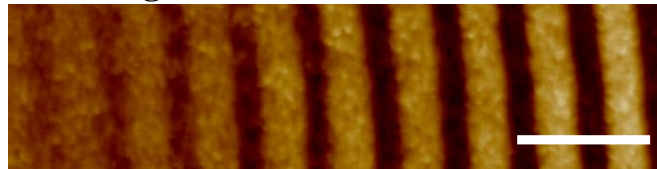
**(b) Modulus**



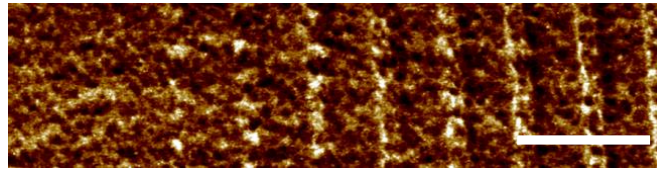
**(c) Adhesion**



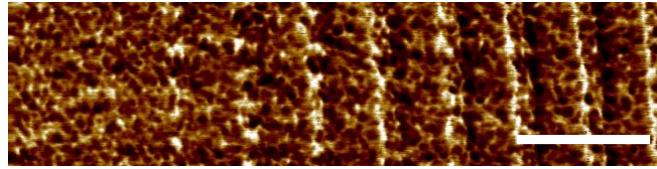
**(d) Height**



**(e) Modulus**



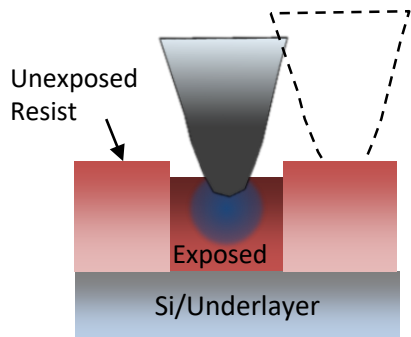
**(f) Adhesion**



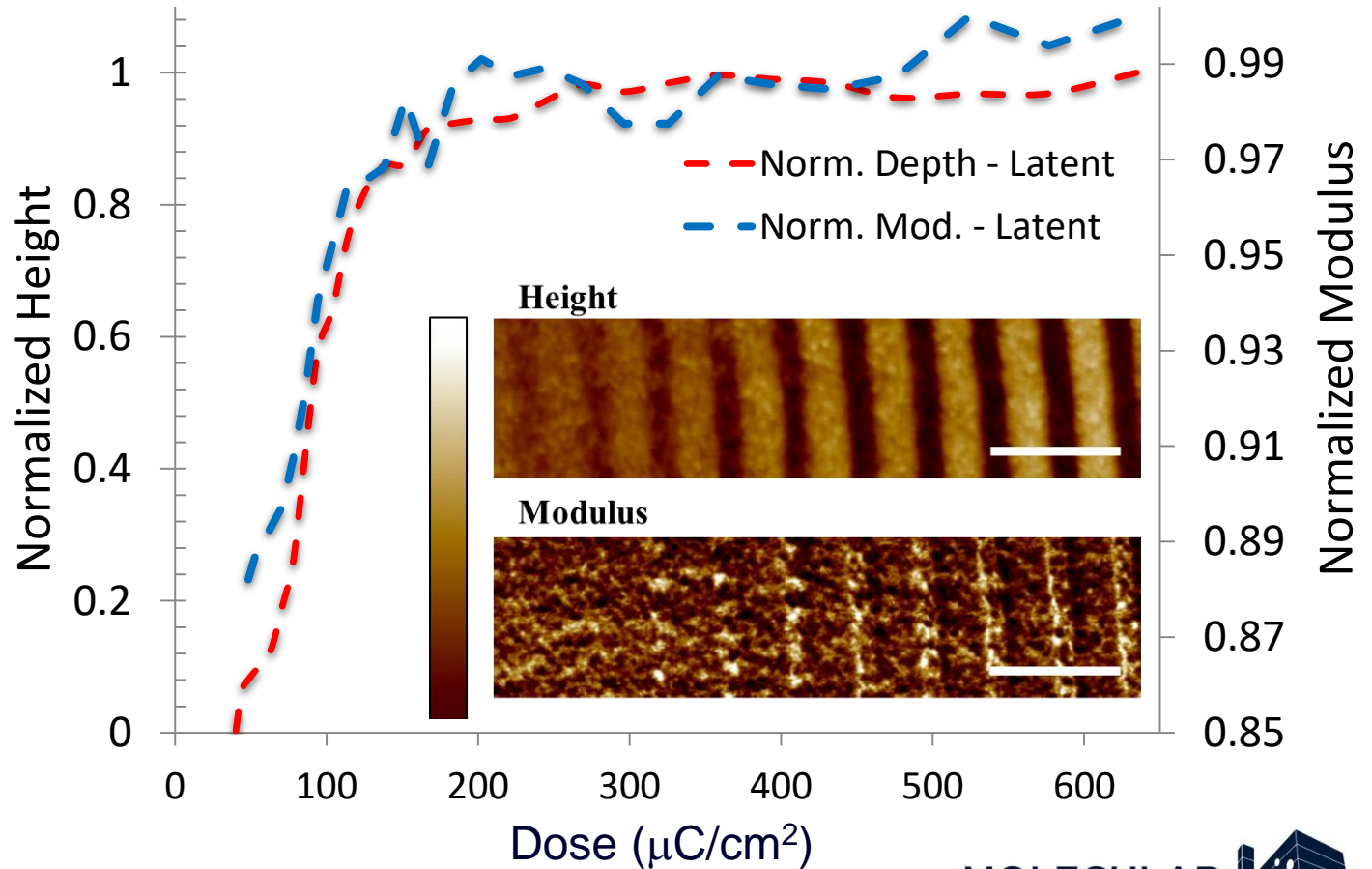
Developed sample

Latent image sample

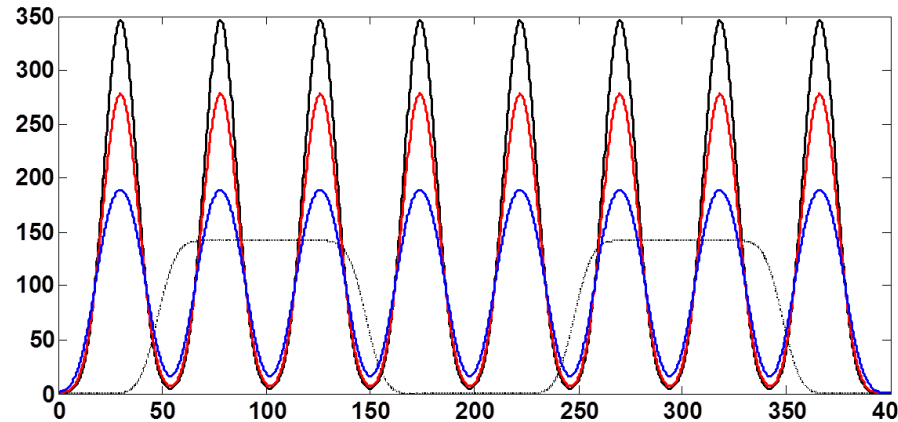
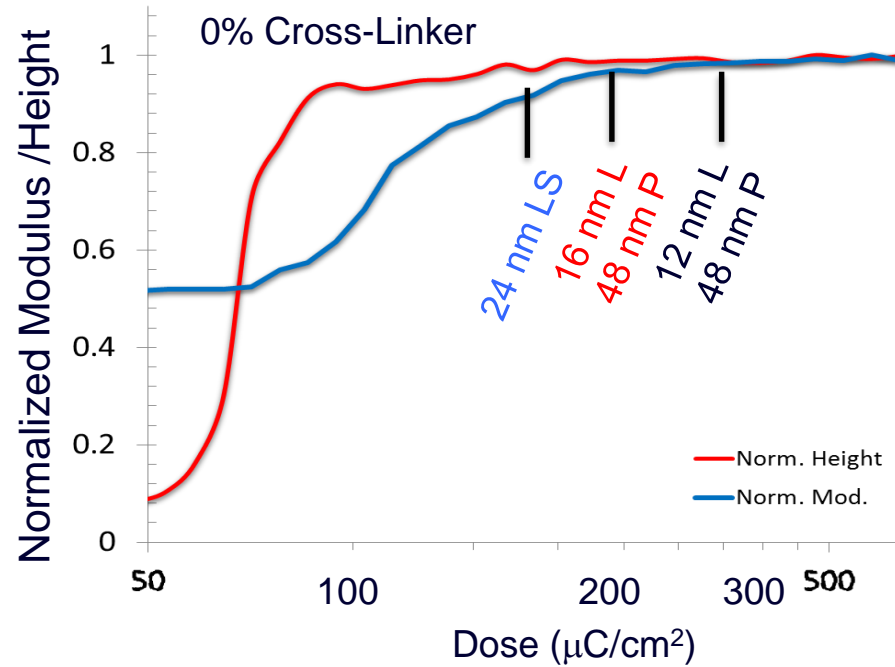
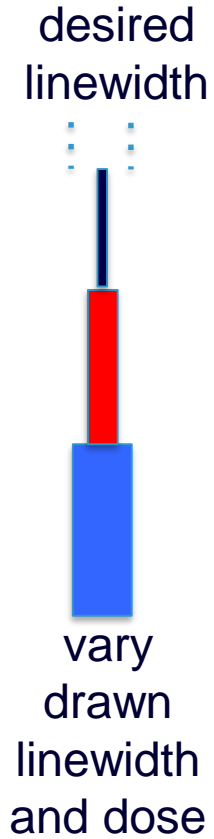
# Latent image depth changes matches modulus



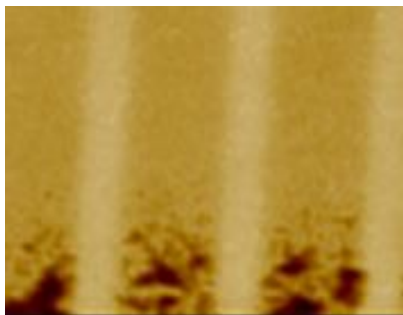
0% Cross-Linker



# Use biasing to improve modulus

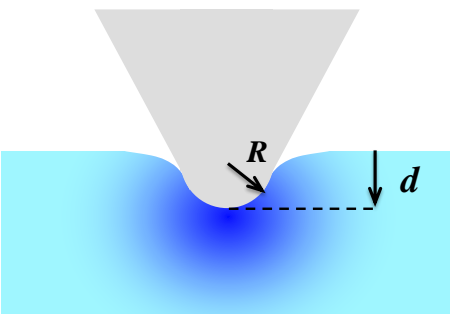


# Conclusions



AFM provides high spatial resolution information of dissolution process

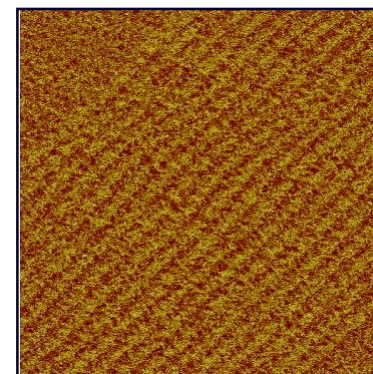
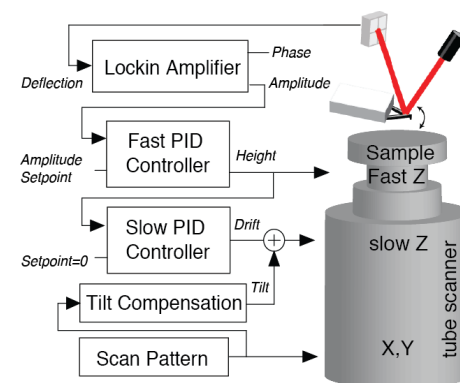
15 frames per second of soft material available with new Z piezo design



Modulus Measurement is a promising high resolution probe of chemistry through dose

Modulus and Latent Image Depth Show Chemistry Far Beyond Full Thickness

Bias Can be Used to Increase Modulus and Reduce Pattern Collapse

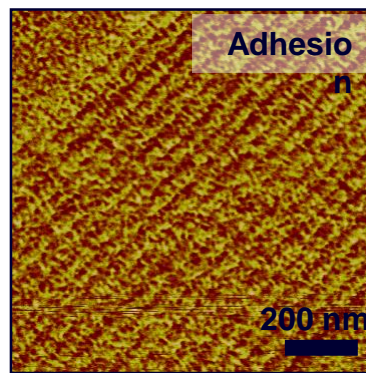
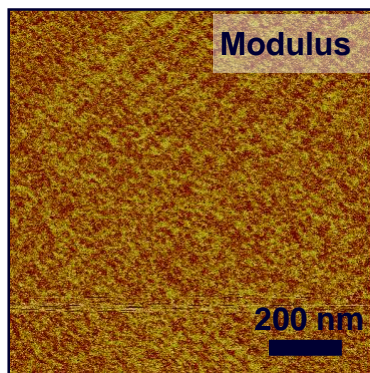
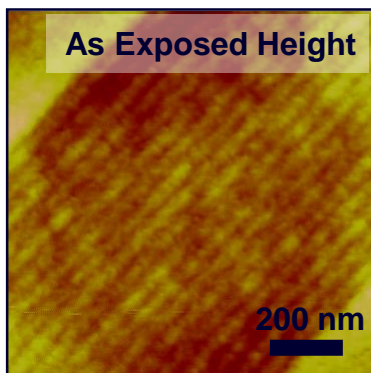




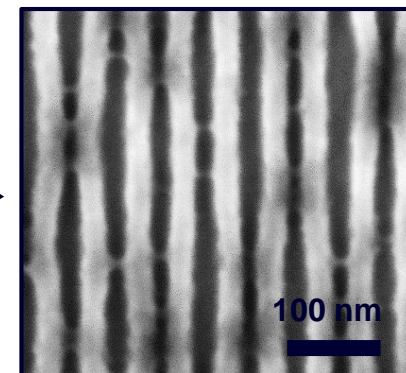
# Improved modulus with bias

No Bias:

24nm-48P

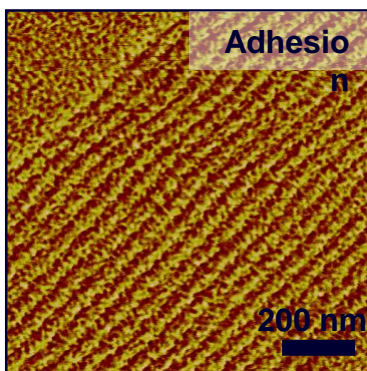
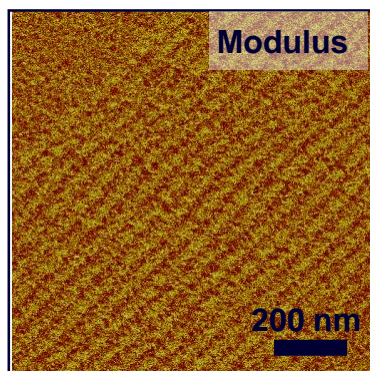
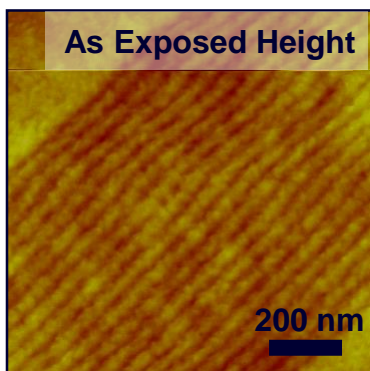


Develop

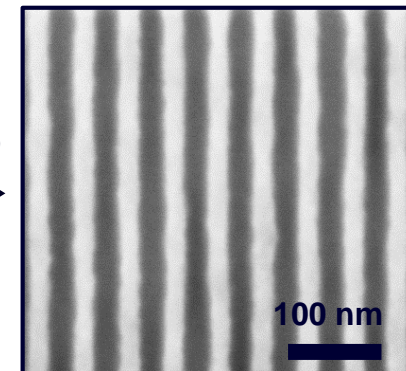


Bias:

20nm-48P



Develop



# High Speed Spiral Scanning

## Calcite Dissolution

Asylum MFP3D

90  $\mu\text{m}$  scanner

Usually 100-200s per image



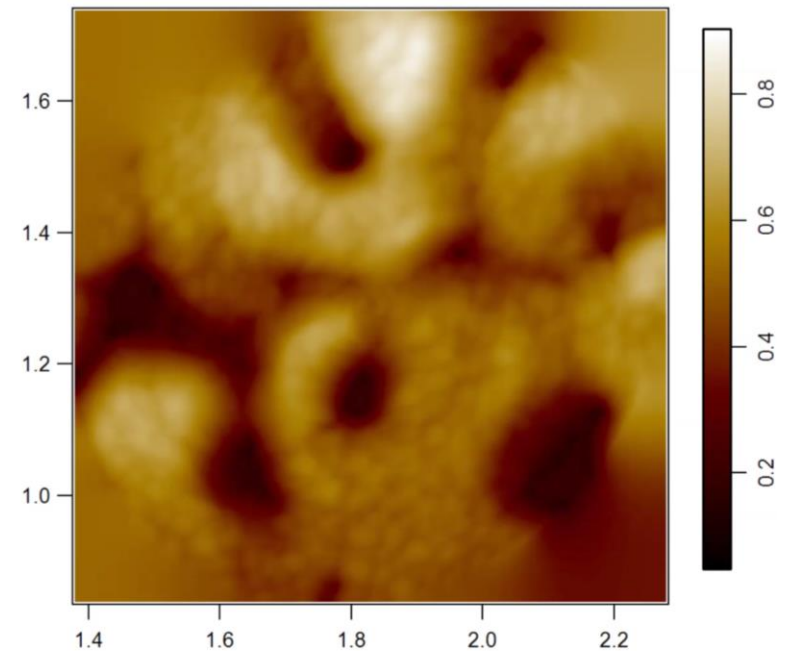
5  $\mu\text{m}$  image  
100 loops  
5s/image

## Fast Survey

Asylum Cypher

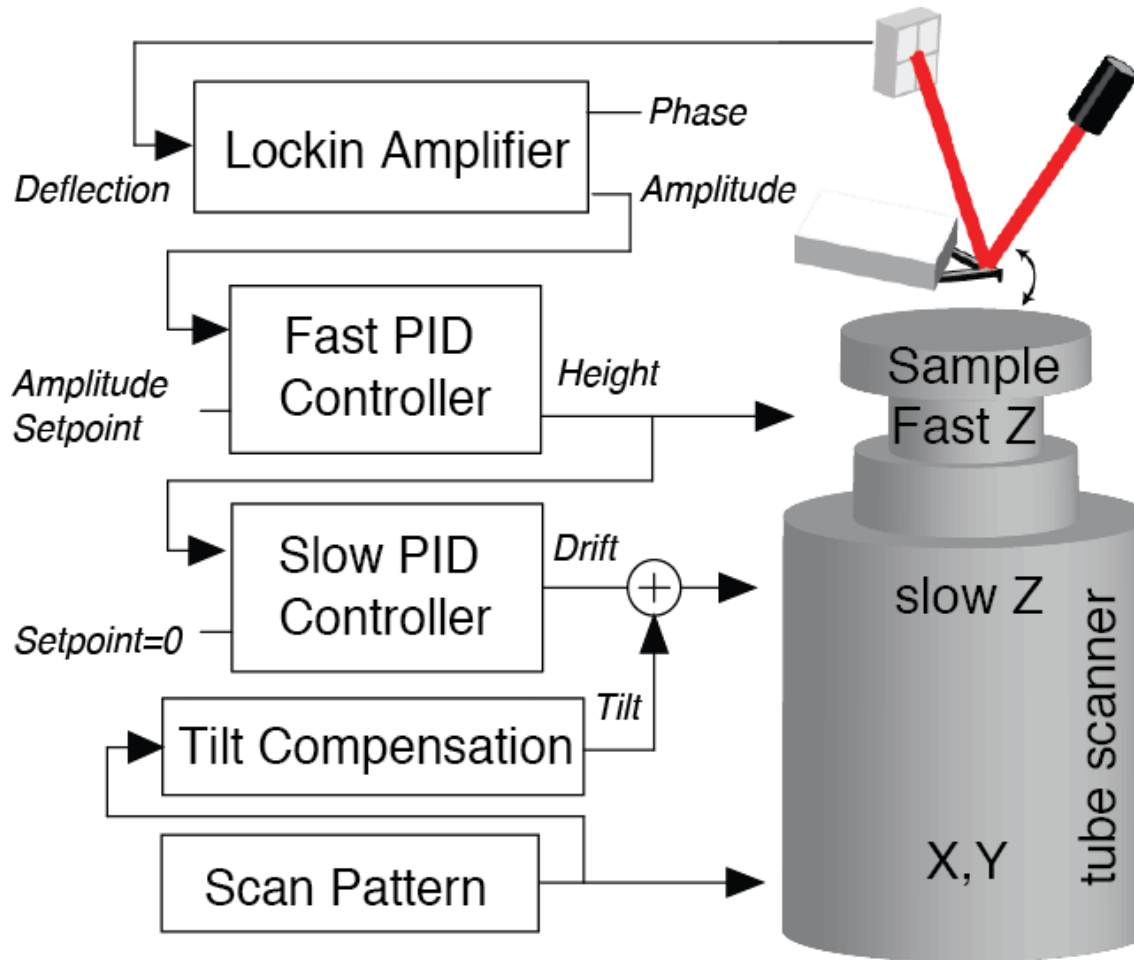
40  $\mu\text{m}$  scanner

Usually 40s per image



1  $\mu\text{m}$  image  
85 loops  
8 frames/s

# Fast Z with tilt correction



Slow Z piezo handles drift and sample tilt.

Fast Z only does topography.